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	<b>Applicant/Patent Owner</b> Stephen P. DeOrnellas		
	<b>Filing/Issue Date</b> June 13, 2001	<b>Group Art Unit</b> 1763	

**U.S. PATENTS**

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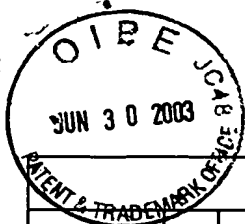
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**U.S. PATENT PUBLICATIONS**

Examiner Initial		Patent Application Publication Number	Publication Date	Applicant

**PENDING U.S. PATENT APPLICATIONS**

Examiner Initial		Application Number	Filing Date	First Named Inventor	Petition to Expunge? Yes   No



## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Publication Date	Country	Class	Subclass	Trans- lation	
						Yes	No
	JP-7-130712 /	5/19/1995	Japan				

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GAG	Ohno, et al. <i>Reactive Ion Etching of Cooper Films in SiCl<sub>4</sub> and N<sub>2</sub></i> , Japanese Journal of Applied Physics, Vol. 28, No. 6, June 1978, pp. 11070-1072 /
GAG	Krogh, et al. <i>Spectroscopic Diagnostic of Temperature-Controlled Trench Etching of Silicon</i> , Plasma Chemistry Plasma Processes, 10(2), 1990, pp. 231-233, 239 /

Examiner

George Goudreau

Date Considered

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